



AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions and listings of claims in the application.

LISTING OF CLAIMS

1. (Currently Amended) A substrate for a liquid crystal device, comprising:

a planar region and a roughened region, the roughened region comprising microscopic peaks and valleys, tops of the peaks in the roughened region having heights substantially equal to, or less than, a plane of the planar region,

wherein a predetermined mark made of a metal film is formed on the planar region, and a reflecting film made of the same metal film is formed on both the microscopic peaks and valleys in the roughened region, and the predetermined mark is separated from the reflecting film;

wherein a surface of the reflecting film corresponds to the microscopic peaks and valleys of the roughened region for yielding predetermined scattering characteristics during a reflective display.

2. (Cancelled)

3. (Previously Presented) The substrate for a liquid crystal device according to Claim 1, wherein the predetermined mark is an alignment mark.

4. (Previously Presented) The substrate for a liquid crystal device according to Claim 1, wherein the predetermined mark is a process control mark.

5. (Original) The substrate for a liquid crystal device according to Claim 1, wherein wiring is formed in the planar region.

6. (Original) The substrate for a liquid crystal device according to Claim 1, wherein a sealant is formed in the planar region.

7. (Previously Presented) The substrate for a liquid crystal device according to Claim 1, wherein the maximum height R_y , the arithmetic mean roughness R_a , the ten-point average roughness R_z , and the mean wavelength S_m in the roughened region are in predetermined ranges.

8. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 0.2 to 3 μm , the arithmetic mean roughness R_a is set at 0.02 to 0.3 μm , the ten-point average roughness R_z is set at 0.1 to 2.5 μm , and the mean wavelength S_m is set at 4 to 60 μm .

9. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 1.5 to 2.0 μm , the arithmetic mean roughness R_a is set at 0.15 to 0.3 μm , the ten-point average roughness R_z is set at 1.3 to 1.8 μm , and the mean wavelength S_m is set at 15 to 25 μm .

10. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 0.7 to 1.2 μm , the arithmetic mean roughness R_a is set at 0.1 to 0.2 μm , the ten-point average roughness R_z is set at 0.5 to 1.0 μm , and the mean wavelength S_m is set at 35 to 50 μm .

11. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 0.6 to 1.2 μm , the arithmetic mean roughness R_a is set at 0.05 to 0.15 μm , the ten-point average roughness R_z is set at 0.5 to 1.0 μm , and the mean wavelength S_m is set at 15 to 25 μm .

12. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 0.4 to 1.0 μm , the arithmetic mean roughness R_a is set at 0.04 to 0.10 μm , the ten-point average roughness R_z is set at 0.3 to 0.8 μm , and the mean wavelength S_m is set at 8 to 15 μm .

13. (Original) The substrate for a liquid crystal device according to Claim 7, wherein the maximum height R_y is set at 0.8 to 1.5 μm , the arithmetic mean roughness R_a is set at 0.05 to 0.15 μm , the ten-point average roughness R_z is set at 0.7 to 1.3 μm , and the mean wavelength S_m is set at 8 to 15 μm .

14. (Previously Presented) The liquid crystal device comprising a liquid crystal layer interposed between a substrate for a liquid crystal device according to Claim 1 and another substrate.

15. (Original) The electronic apparatus comprising a liquid crystal device according to Claim 14.

16-23. (Cancelled)

24. (Previously Presented) The substrate for a liquid crystal device according to Claim 1, wherein the substrate contains a first composition which is

network-shaped and a second composition located in spaces of the network-shaped first composition, and the microscopic peaks and valleys are formed on a surface of the roughened region corresponding to the network-shape of the first composition.

25. (Currently Amended) A substrate for a liquid crystal device, comprising:

a surface having a planar region and a roughened region, the roughened region comprising microscopic peaks and valleys, tops of the peaks in the roughened region having heights substantially equal to, or less than, a plane of the planar region,

wherein a predetermined mark made of a metal film is formed on the planar region, and a reflecting film made of the same metal film as the predetermined mark is formed on the roughened region, and the predetermined mark is separated from the reflecting film;

wherein a surface of the reflecting film corresponds to the microscopic peaks and valleys of the roughened region for yielding predetermined scattering characteristics during a reflective display.

26. (Previously Presented) The substrate for a liquid crystal device according to Claim 25, wherein the metal film is composed of an elemental metal, such as aluminum or silver, or an alloy containing aluminum, silver, chromium, or the like, as the principal ingredient.

27. (New) A substrate for a liquid crystal device, comprising:

- a first surface;
- a second surface opposite the first surface, the second surface including:
 - a roughened region of microscopic peaks and valleys recessed from the second surface; and
 - a planar region adjacent the roughened region;
- wherein each peak has a height substantially equal to or less than a plane of the planar region;
- a metal alignment mark disposed on the second surface within the planar region and spaced apart from the roughened region; and
- a metal reflecting film disposed on the peaks and valleys in the roughened region and spaced apart from the alignment mark, the reflecting film having a reflective surface with a shape corresponding to the peaks and valleys to yield predetermined scattering characteristics;
- wherein the alignment mark and the reflecting film are separate portions of the same metal film.